## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination | CHEN ET AL. | Examiner | Art Unit | Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	А	US-6,642,863 B1	11-2003	Venkitachalam et al.	341/61
	B	US-6,356,968 B1	03-2002	Kishon, Jakob	710/306
	С	US-5,787,259 A	07-1998	Haroun et al.	709/253
	D	US-2004/0107271 A1	06-2004	Ahn et al.	709/219
	E	US-2002/0002035 A1	01-2002	Sim et al.	455/41
	F	US-2003/0163666 A1	08-2003	Cupps et al.	712/1
	G	US-2004/0006484 A1	01-2004	Manis et al.	704/500
	н	US-6,661,360 B2	12-2003	Lambert, Russell H.	341/131
	-	US-6,597,687 B1	07-2003	Rao, Vijay M.	370/352
	J	US-2002/0177915 A1	11-2002	Kawamura et al.	700/94
	к	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	O					
	R				·	
	S					
	Т					

## NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.